

STGP10NC60H

N-CHANNEL 10A - 600V - TO-220 VERY FAST PowerMESH™ IGBT

TARGET SPECIFICATION

General features

Туре	V _{CES}	V _{CE(sat)} (Max)@ 25°C	I _C @100°С
STGP10NC60H	600V	< 2.5V	10A

- LOWER ON-VOLTAGE DROP (V_{cesat})
- LOWER C_{RES} / C_{IES} RATIO (NO CROSS-CONDUCTION SUSCEPTIBILITY)
- VERY SOFT ULTRA FAST RECOVERY ANTIPARALLEL DIODE

Description

Using the latest high voltage technology based on a patented strip layout, STMicroelectronics has designed an advanced family of IGBTs, the PowerMESH[™] IGBTs, with outstanding performances. The suffix "H" identifies a family optimized for high frequency applications in order to achieve very high switching performances (reduced tfall) mantaining a low voltage drop.

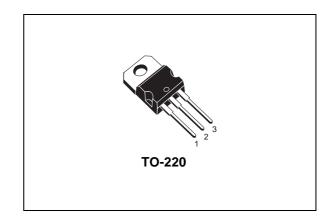
Applications

- HIGH FREQUENCY MOTOR CONTROLS
- SMPS and PFC IN BOTH HARD SWITCH AND RESONANT TOPOLOGIES
- MOTOR DRIVERS

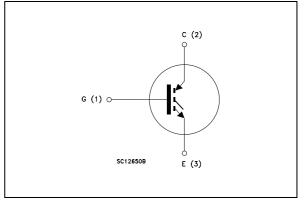
Order codes

Sales Type	Marking	Package	Packaging	
STGP10NC60H	STGP10NC60H P10NC60H		TUBE	

Rev 1 1/9



Internal schematic diagram



1 Electrical ratings

Symbol	Parameter	Value	Unit	
V _{CES}	Collector-Emitter Voltage (V _{GS} = 0)	600	V	
I _C Note 5	Collector Current (continuous) at T _C = 25°C	20	А	
I _C Note 5	Collector Current (continuous) at T _C = 100°C	10	А	
I _{CM} Note 1	Collector Current (pulsed)	40	W	
V _{GE}	Gate-Emitter Voltage	±20	А	
P _{TOT}	Total Dissipation at T _C = 25°C	60	W	
T _{stg}	Storage Temperature	– 55 to 150	°C	
Тj	Operating Junction Temperature			
Τ _Ι	Maximum Lead Temperature For Soldering Purpose (for 10sec. 1.6 mm from case)			

Table 1. Absolute maximum ratings

Table 2.Thermal resistance

Rthj-case	Thermal Resistance Junction-case Max	2.08	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	62.5	°C/W



2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified)

Table	3	On/Off
Table	J.	

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{BR(CES)}	Collector-Emitter Breakdown Voltage	I _C = 1mA, V _{GE} = 0	600			V
I _{CES}	Collector cut-off Current $(V_{GE} = 0)$	V _{CE} = Max Rating,T _C = 25°C V _{CE} =Max Rating,T _C = 125°C			10 1	μA mA
I _{GES}	Gate-Emitter Leakage Current (V _{CE} = 0)	V_{GE} = ±20V , V_{CE} = 0			±100	nA
V _{GE(th)}	Gate Threshold Voltage	$V_{CE} = V_{GE}, I_C = 250 \mu A$	5		7	V
V _{CE(sat)}	Collector-Emitter Saturation Voltage	V _{GE} = 15V, I _C = 5A V _{GE} = 15V, I _C = 5A, Tc= 125°C		1.9 1.7	2.5	V V
9 _{fs}	Forward Transconductance	V _{CE} = 15V _, I _C = 5A		TBD		S

Table 4. Dynamic

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
C _{ies} C _{oes} C _{res}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{CE} = 25V, f = 1MHz,V _{GE} = 0		TBD TBD TBD		pF pF pF
Q _g Q _{ge} Q _{gc}	Total Gate Charge Gate-Emitter Charge Gate-Collector Charge	V_{CE} = 390V, I _C = 5A, V_{GE} = 15V, (see Figure 2)		TBD TBD TBD		nC nC nC



Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r (di/dt) _{on}	Turn-on Delay Time Current Rise Time Turn-on Current Slope	$V_{CC} = 390$ V, $I_C = 5$ A R _G = 10 Ω , V_{GE} = 15V, Tj= 25°C (see Figure 3)		TBD TBD TBD		ns ns A/µs
t _{d(on)} t _r (di/dt) _{on}	Turn-on Delay Time Current Rise Time Turn-on Current Slope	$V_{CC} = 390V$, $I_C = 5A$ $R_G = 10\Omega$, $V_{GE} = 15V$, Tj=125°C (see Figure 3)		TBD TBD TBD		ns ns A/µs
t _r (V _{off}) t _d (_{off}) t _f	Off Voltage Rise Time Turn-off Delay Time Current Fall Time	$V_{cc} = 390V, I_C = 5A,$ $R_{GE} = 10\Omega, V_{GE} = 15V, T_J = 25^{\circ}C$ (see Figure 3)		TBD TBD TBD		ns ns ns
t _r (V _{off}) t _d (_{off}) t _f	Off Voltage Rise Time Turn-off Delay Time Current Fall Time	$V_{cc} = 390V$, $I_C = 5A$, $R_{GE}=10\Omega$, $V_{GE} = 15V$, Tj=125°C (see Figure 3)		TBD TBD TBD		ns ns ns

Table 5. Switching On/Off (inductive load)

 Table 6.
 Switching energy (inductive load)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Eon Note 3 E _{off} Note 4 E _{ts}	Turn-on Switching Losses Turn-off Switching Losses Total Switching Losses	$V_{CC} = 390$ V, $I_C = 75$ A R _G = 10 Ω , V_{GE} = 15V, Tj= 25°C (see Figure 3)		TBD TBD TBD		μJ μJ μJ
	Turn-on Switching Losses Turn-off Switching Losses Total Switching Losses	$V_{CC} = 390V, I_C = 5A$ $R_G = 10\Omega, V_{GE} = 15V, Tj = 125°C$ (see Figure 3)		TBD TBD TBD		μJ μJ

(1)Pulse width limited by max. junction temperature

(2) Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%

(3) Eon is the tun-on losses when a typical diode is used in the test circuit in figure 2 Eon include diode recovery energy. If the IGBT is offered in a package with a co-pak diode, the co-pack diode is used as external diode. IGBTs & Diode are at the same temperature (25°C and 125°C)

(4) Turn-off losses include also the tail of the collector current

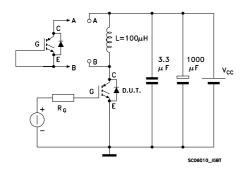
(5) Calculated according to the iterative formula:

$$I_{C}(T_{C}) = \frac{T_{JMAX} - T_{C}}{R_{THJ-C} \times V_{CESAT(MAX)}(T_{C}, I_{C})}$$



3 Test Circuits

Figure 1. Test Circuit for Inductive Load Switching



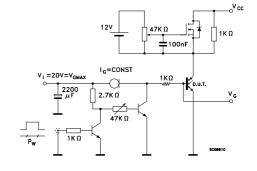
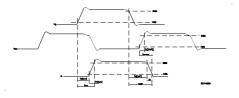


Figure 2. Gate Charge Test Circuit

Figure 3. Switching Waveform



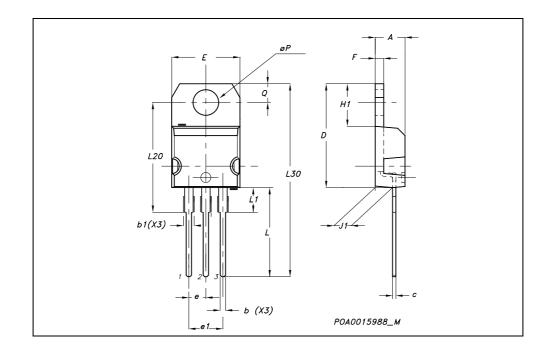


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com



		TO-220 I	MECHANIC	AL DATA		
DIM.		mm.			inch	
DINI.	MIN.	TYP	MAX.	MIN.	TYP.	MAX
А	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.15		1.70	0.045		0.066
С	0.49		0.70	0.019		0.027
D	15.25		15.75	0.60		0.620
E	10		10.40	0.393		0.409
е	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.052
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
øP	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116





5 Revision History

Date	Revision	Changes
18-Nov-2005	1	Initial release.



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